

4F, NO. 16, Sec. 2 Chung Yang S Rd., Peitou, Taipei, Taiwan. TEL : 886-2-2894-1202 , 886-2-2895-2201 FAX : 886-2-2894-1206 , 886-2-2895-6207

SPECIFICATION FOR APPROVAL					
CUSTOMER	:				
PRODUCT TYPE	SMD TSX 2.5 × 2.0				
NOMINAL FREQ.	<u>19.2 MHz</u>				
TXC P/N	: OZ19270001				
REVISION	: <u>A2</u>				
CUSTOMER P/N	:				
PM / SALES	:				
DATE	:				
CUSTOMER SIGN	ATURE & DATE				

- (1) TXC requires one copy returned with signature and title of authorized individual that signifies acceptance of the attached specifications.
- (2) Orders received and accepted by TXC after return of signed copy of specification will be produced per these specifications.
- (3) Any changes to these specifications must be agreed upon by both parties and new revision of the Product Specification Sheet will be issued.
- (4) Any issuance of purchase order prior to consigning back the Approval page of "Specification Sheets" from customers will be regarded as the agreement on the contents of these specifications.

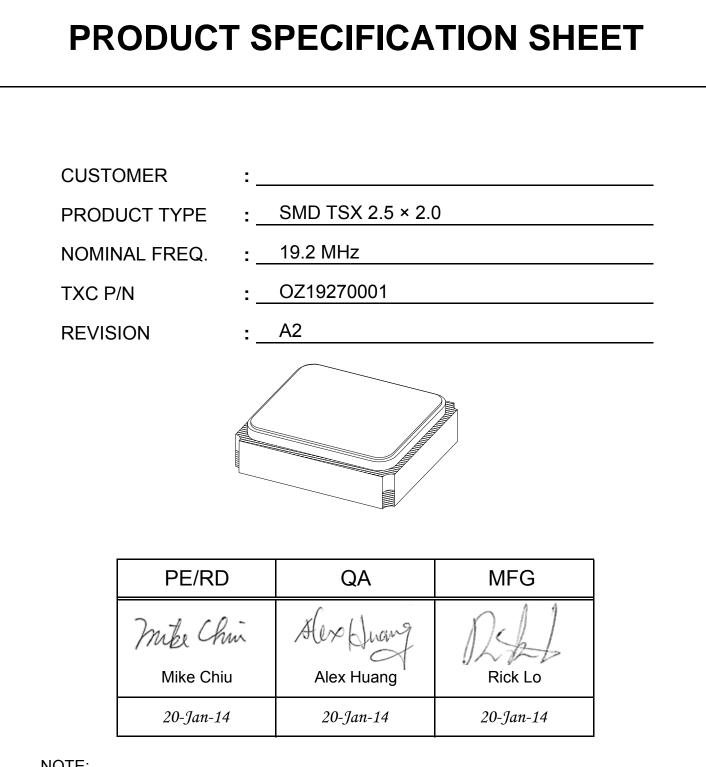
Attachment(s):

- V 1. Product Specification Sheet
 - 2. Testing Report(Electrical & Temperature)
- 3. Reliability Report

RoHS Compliant

TXC CORPORATION 4F, NO. 16, Sec. 2 Chung Yang S Rd., Peitou, Taipei, Taiwan.

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NOTE:

- (1) Lead Free Products are " Directive 2002 / 95 / EC of The European Parliament of 27 January 2003 on the restriction of the use of certain hazardous substances (RoHS) in electrical and electronic equipment" Compliant (Attachment: SGS Test Report).
- (2) Revision "Sx" is for engineering samples only. PE/RD's approval required.
- (3) Revision "Ax" is production ready. PE, QA and MFG's approval required.

RoHS Compliant

SMD TSX 2.5 × 2.0

PRODUCT TYPE :

REVISION : A2

P/N: OZ19270001

Rev Revise page Date Ref.No. **Reviser** Revise contents A1 N/A Initial released 27-Jun-12 N/A Yachuan Miao 2 EC-PCF-140117-02 A2 Change ESR:80 Ohm to 70 Ohm 20-Jan-14 Yachuan Miao



PRODUCT TYPE : SMD TSX 2.5 × 2.0

CRYSTAL ELECTRICAL SPECIFICATIONS

Standard Atmospheric Conditions

Unless otherwise specified, the standard range of atmospheric conditions for making measurement

and tests are as follow:

Ambient temperature : 30±10°C

Relative humidity : 40%~70%

If there is any doubt about the results, measurement shall be made within the following limits:

Ambient temperature : 30±3°C

Relative humidity : 40%~70%

Measurement Equipment

Electrical characteristics measured by HP E5100A or equivalent

Crystal Cutting Type

The crystal is using AT CUT (thickness shear mode)

	Devenue (cons	Cumhal	Condition		Electric	al Spec.		Note	
	Parameters	Symbol	Condition	Min.	Тур.	Max.	Units	Note	
1	Nominal Frequency	FL		19.200000			MHz		
2	Oscillation Mode	-		F	undamenta	al			
3	Load Capacitance	CL			7		pF	1	
4	Frequency Tolerance	-	+30°C ± 3°C			±10	ppm		
5	Tolerance Over Temperature	-	-30 to +85°C			±12	ppm	2	
6	Frequency Drift After Reflow	-	two reflows			±2	ppm		
7	Operating Temperature	-		-30		+105	°C		
8	Aging	-				±0.7	ppm/Year		
9	Drive Level	DL		10		100	μW		
10	Effective Resistance Rr	Rr				70	Ω		
11	Shunt Capacitance C0	C0		0.3		1.3	pF		
12	Motional Capacitance C1	C1		1.8		3.1	fF		
13	Insulation Resistance	-	at DC 100 V	500			MΩ		
14	Storage Temperature Range	-	-	-40		+105	°C		
15	Spurious Mode Series Resistance	-	±1 MHz	1100			Ω		
16	Q Factor	Q		75000				3	
17	First-order Curve Fitting Parameter	-		-0.4		-0.1	ppm/°C	4	
18	Second-order Curve Fitting Parameter	-		-4.5	0	4.5	x10 ⁻⁴ ppm/°C ²	4	
19	Third-order Curve Fitting Parameter	-		8.5	10	11.5	x10 ⁻⁵ ppm/°C ³	4	
20	Residual frequency stability slope	-				±50	ppb/°C	5	
21	5°C small orbit hysteresis 1	-				±50	ppb/°C	6	
22	5°C small orbit hysteresis 2	-			100		ppb pk-pk	7	

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	Parameters	Symbol Condition		Electrical Spec.				
		Symbol	Condition	Min.	Тур.	Max.	Units	Note
23	DLD Freq (Max-Min)	-				3.0	ppm	8
24	DLD Freq (Repeatability)	-				0.7	ppm	8
25	DLD ESR (Max-Min)	-				±20	%	8
26	DLD ESR (Repeatability)	-				±10	%	8

Note 1 The load capacitance is measured according to IEC Standard #60444-7

Note 2 Above 85°C tolerance over temperature bound by third-order coefficient range

Note 3 Minimum Q value calculated from ESR and L is smaller than this specification

Note 4 The curve fitting parameter is obtained from the Qualcomm crystal curve fitting algorithm, t0=30 °C (Refer to Curve Fitting Calculation Table: 80-V9690-23)

Note 5 Condition 1A – Test condition (continuous temperature rate change of ~1.0°C/min):

- □ Measure FT points every 1°C, heating up from -30 to +85°C, subtract a fifth-order polynomial best fit and then calculate the slope of the residual.
- \Box The residual slope should be within ±50 ppb/°C.

Note 6 Condition 1B – Hysteresis 1 test condition (continuous temperature rate change of ~1.0°C/min):

- Measure FT points every 0.5°C while cycling temperature over a 5°C small temperature orbit; an example 5°C small orbit temperature cycle is +30°C to +35°C to +30°C.
- During every individual heating/cooling cycle there should be 11 points; discard the first point of each heating and cooling cycle; this leaves 10 points for each heating and cooling cycle. Subtract the fifth-order polynomial best fit from 1A for each of the 10 points, and then calculate the slope of the residual for each of these heating and cooling 10 point curves.
- $\hfill\square$ The residual slope should be within ±50 ppb/°C.

Note 7 Hysteresis 2 test condition (continuous temperature rate change of ~1.0°C/min):

- Measure FT points every 0.5°C while cycling temperature over a 5°C small temperature orbit; an example 5°C small orbit temperature cycle is +30°C to +35°C to +30°C.
- During every individual heating/cooling cycle there should be 11 points; discard the first and last point of each heating and cooling cycle, which results in 9 temperature points. Calculate the average measured peak-to-peak frequency difference for these 9 temperature points.
- □ The average difference is the magnitude of the small orbit hysteresis 2.

Note 8 0.01 uW to 100 uW to 0.01 uW, number of points: 15 points up and 15 points down = 29 total data points

Note 9 This crystal specification complies to Qualcomm Mini-Specification 80-V9690-24 Rev. D

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P/N : OZ19270001 RE

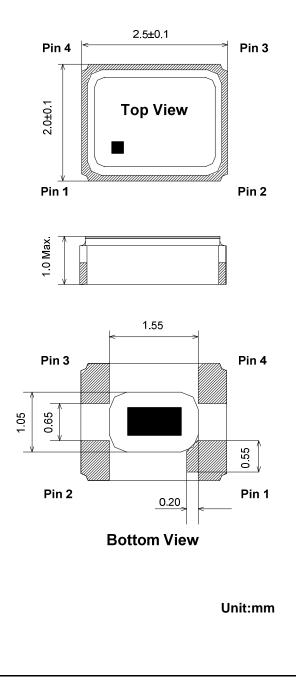
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NTC THERMISTOR ELECTRICAL SPECIFICATIONS

	Parameters	Symbol	Condition		Note			
		Symbol	Condition	Min.	Тур.	Max.	Units	Note
1	Resistance (25 °C)			100k ± 1% Ω				
2	B-Constant (25-50 °C)			4250 ± 1% K			К	1
3	Operating Temperature			-30		+105	°C	

Note 1 The B constant is calculated using the zero-power resistance values measured at 25°C and 50°C

DIMENSIONS

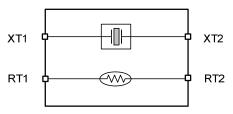


PIN FUNCTION

	Symbol	Function
Pin 1	XT1	XTAL Terminal 1
Pin 2	RT2	Thermistor Terminal 2
Pin 3	XT2	XTAL Terminal 2
Pin 4	RT1	Thermistor Terminal 1

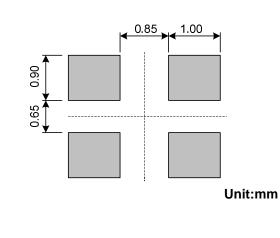
Note: Pin 2 is connected to the metal lid and thermistor Pin 4 is connected to the thermistor only

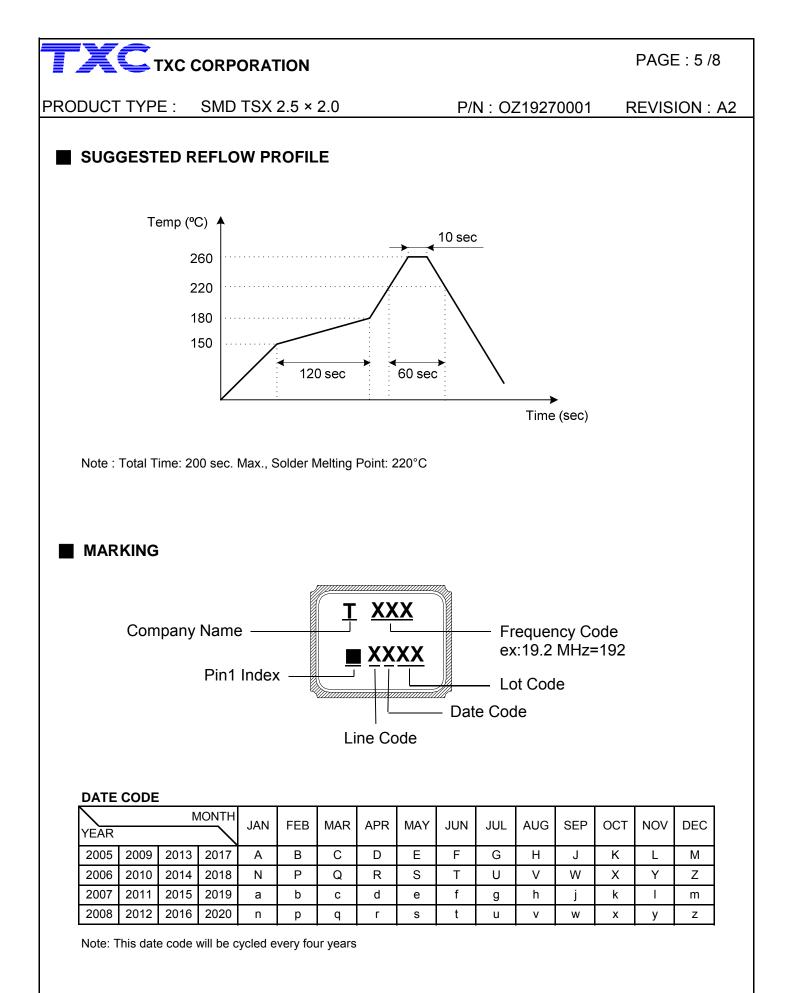
BLOCK DIAGRAM



Note: RT2 shall be connected to GND is recommended

SUGGESTED LAYOUT

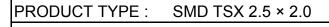




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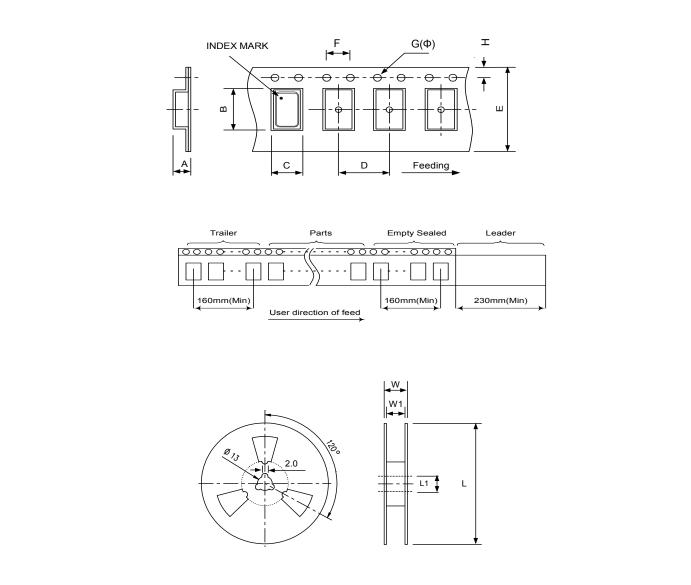
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PACKING :



Unit: mm

DIMENSIONS	А	В	С	D	E	F	G	Н	L	L1	W	W1	Standard Reel Quantity
(mm)	1.15	2.70	2.25	4.00	8.00	4.00	1.55	1.75	178	13.0	11.6	8.4	is 3,000 pcs per reel

WEIGHT

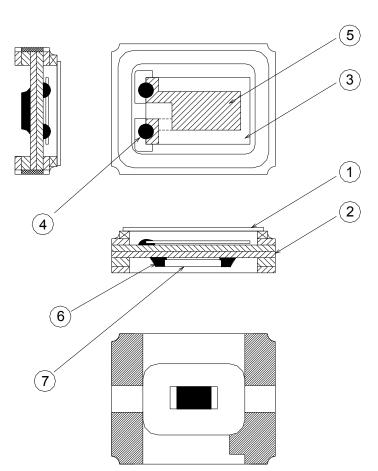
0.0135 g / piece(TYP), 40 \pm 2 g /3 kpcs(regardless of tape weight)

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STRUCTURE ILLUSTRATION

Crystal Enclosure Seal : Seam Welding



No.	COMPONENTS	MATERIALS	FINISH/SPECIFICATIONS
1	Lid	Metal (Fe+Co+Ni)	-
2	Base (Package)	Ceramic (Al ₂ O ₃) + Kovar (Fe+Co+Ni) + Ag/Cu	Alumina Ceramics
3	Crystal Blank	SiO ₂	-
4	Conductive Adhesive	Ag	Silicone Resin
5	Electrode	Noble Metal	-
6	Solder	Sn	-
7	Thermistor	Al ₂ O ₃ , Ag, Ni	-

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RELIABILITY SPECIFICATIONS

1. Mechanical Endurance

No.	Test Item	Test Me	ethods	Reference
1.1	Drop Test	150 cm height, 3 times on concrete	floor.	JIS C6701
1.2	Mechanical Shock	Device are shocked to half sine way	/e(1000 G)three mutually	MIL-STD-202
1.2		perpendicular axes each 3 times. 0.	5 msec. duration time	WIIL-31D-202
		Frequency range	10 ~ 2000 Hz	
		Amplitude	1.52 mm/20 G	
1.3	Vibration	Sweep time	20 minutes	MIL-STD-883
		Perpendicular axes each test time	4 Hrs	
			(Total test time 12 Hrs)	
1.4	Gross Leak	Standard sample for automatic gros	ss leak detector	
1.4	GIUSS LEak	Test pressure: 2 kg / cm ²		MIL-STD-883
1.5	Fine Leak	Helium bombing 4.5 kg/ cm ² for 2	Hrs	
		Temperature	245°C ± 5°C	
		Immersing depth	0.5 mm minimum	
1.6	Solderability	Immersion time	5 ± 1 seconds	MIL-STD-883
		Flux	Rosin resin methyl alcohol	
			solvent(1:4)	

2. Environmental Endurance

No.	Test Item	Test Methods	Reference
		Pre-heat temperature 125°C	
2.1		Pre-heat time 60 ~ 120 sec.	MIL-STD-202
2.1	Heat	Test temperature 260 ± 5°C	
		Test time 10 ± 1 sec.	
2.2	High Temp. Storage	+ 125 °C ± 3 °C for 500 ± 12 Hrs	MIL-STD-883
2.3	Low Temp. Storage	- 40°C ± 3°C for 500 ± 12 Hrs	MIL OID 000
2.4	Thermal Shock	Total 100 cycles of the following temperature cycle $125 \pm 3^{\circ}C$ $-55 \pm 3^{\circ}C$ 30 min. 10 min. max.	MIL-STD-883
2.5	High Temp & Humidity	85°C ± 3°C, RH 85% , 500 Hrs	JIS C5023

单击下面可查看定价,库存,交付和生命周期等信息

>>TXC(台湾晶技)